

# Search Notes



Application/Control No.

10/825,202

Examiner

Tae H. Yoon

Applicant(s)/Patent under  
Reexamination

HARAGUCHI ET AL.

Art Unit

1714

## SEARCHED

Class	Subclass	Date	Examiner
524	445	3/27/07	Z
523	216		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
BASJ	7/27/07	Z
Zimmer Search		